

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: KOBAYASHI, et al.

JC20 Rec'd PCT/PTO 18 OCT 2005

Serial No.: Not Yet Assigned

Filed: October 18, 2005

Title: Molecular Detection Method, Molecular Counting Method, Molecular Localization Detection Method, and Molecular Detection Sytem Used Therefor

INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR 1.97 & 1.98

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

October 18, 2005

Sir:

In the matter of the above-identified application, applicants are submitting herewith a copy of the documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

This information disclosure statement is being submitted with the new application.

To the extent that the documents listed on the attached form equivalent to Form PTO-1449 are not in the English language, the requirement of 37 CFR 1.98(a)(3) for a concise explanation of the relevance is satisfied by an abstract and the discussion of these documents in the specification.

It is respectfully requested that this information disclosure statement be considered by the Examiner.

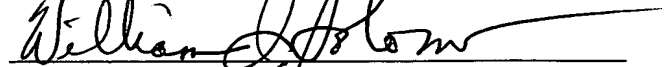
10/553747

EC20 Rec'd PSE/FTO 18 OCT 2009

Please charge any shortage in the fees due in connection with the filing of this paper, including excess claim fees, to Deposit Account No. 01-2135 (1204.45527X00), and please credit any excess fees to such deposit account.

Respectfully submitted,

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Substitute for form 1449A/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	10/553747
		Filing Date	October 18, 2005
		First Named Inventor	Teruyuki KOBAYASHI et al.
		Art Unit	
		Examiner Name	
Sheet 1 of 2	Attorney Docket Number	1204.45527X00	

U.S. PATENT DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)				
		US-				
		US-				
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FOREIGN PATENT DOCUMENTS							
Examiner Initials ¹	Cite No. ¹	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)					
		JP 6-289017		10/18/1994			Abs
		JP 2001-124687		05/11/2001			Abs
		JP 3386883		01/10/2003			Abs
		JP 2003-43037		02/13/2003			Abs
		WO 01/83674		11/08/2001			

Examiner Signature		Date Considered	
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This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Substitute for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known	
				Application Number	10/553747
				Filing Date	October 18, 2005
				First Named Inventor	Teruyuki KOBAYASHI et al.
				Group Art Unit	
				Examiner Name	
Sheet	2	of	2	Attorney Docket Number	1204.45527X00

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		Janese C. O'Brien, John T. Stickey, and Marc D. Porter, "Preparation and Characterization of Self-Assembled Double-Stranded DNA (dsDNA) Microarrays for Protein; dsDNA Screening Using Atomic Force Microscopy" Langmuir, American Chemical Society, 28 November 2000 (28.11.00), Vol. 16, No. 24, pp9559 to 9567	
		Soon Jin Oh, Sung Ju Cho, Chang Ok Kim, and Joon Won Park, "Characteristics of DNA Microarrays Fabricated on Various Aminosilane Layers", Langmuir, American Chemical Society, 05 March 2002, Vol. 18, No. 5, pages 1764-1769	
		T.P. Beebe, Jr. T.E. Wilson, et al., "Direct Observation of Native DNA Structures with the scanning Tunneling Microscope", Science Vol. 243 (20 January 1989), pages 370 to 327	
		R.J. Driscoll, et al., "Atomic-scale imaging of DNA using scanning tunneling microscopy", Nature Vol. 346 (19 July 1990), pages 294-296	
		J. Wang and A.J. Bard, "Monitoring DNA Immobilization and Hybridization on Surfaces by Atomic Force Microscopy Force Measurements", Analytical Chemistry, Vol. 73, No. 10, May 15, 2001, pages 2207 to 2212	

Examiner Signature		Date Considered	
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